

# The electronic structure of $K_xC_{60}$ studied by soft x-ray emission spectroscopy

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## INTRODUCTION

The observation of superconductivity in alkali-metal doped fullerides ( $A_3C_{60}$ , A is alkali metal or mixture) has attracted much research attention [1,2]. The resulting electronic structure of doped  $C_{60}$  depends strongly on the character of the doping atom. There are strong chemical interactions and charge transfer processes, as typified by the alkali metal fullerides. Several phases of potassium doped  $C_{60}$  ( $K_xC_{60}$ ) have been identified previously by x-ray measurements. For  $K_3C_{60}$  the structure is still fcc, like  $C_{60}$ , but with a slightly modified lattice parameter,  $K_4C_{60}$  has a bct structure and for  $K_6C_{60}$  the structure is bcc. Increasing the potassium concentration from zero the conductivity increases and reaches a maximum at  $x=3$ , where the conduction band is half filled. Further doping decreases the conductivity and  $K_xC_{60}$  becomes again semiconducting at  $x=6$ .

Soft x-ray emission spectra originate in transitions between valence states and core states, and thus information on the occupied valence states can be gained. In this paper, we report results from soft x-ray absorption and emission studies of the electronic structure of  $C_{60}$  and potassium doped  $C_{60}$ .

## EXPERIMENT

The experiment was performed at beamline 7.0 of the Advanced Light Source (ALS) at Lawrence Berkeley Laboratory. The beamlines both use undulators and spherical-grating monochromators to provide intense, high-resolution soft x-ray radiation. The pure  $C_{60}$  film was made in situ by evaporation of  $C_{60}$  on clean Mo and Fe surfaces in the experiment chamber under vacuum [3]. Subsequent doping with potassium was done using a degassed getter source (SAES Getters, Italy). The approximate concentration of potassium in the  $C_{60}$  films was controlled by monitoring the exposure time of the  $C_{60}$  film to the potassium flux produced at a given getter current (5A). In one case, potassium was deposited onto a room temperature  $C_{60}$  film, while in another case, potassium was deposited onto a hot  $C_{60}$  film (at about 200°C). The diffusion and equilibration of potassium into the  $C_{60}$  film were completed by heating up the film to 200°C under  $10^{-8}$  mbar of potassium vapour pressure.

The x-ray absorption spectra (XAS) were obtained using the total electron-yield-detection (TEY) method, done by measuring the sample current against photon energy of incoming monochromatized synchrotron radiation. The spectra were normalized to the photo-current from a clean gold mesh introduced in the synchrotron radiation beam in order to correct for intensity variations in the excitation beam.

The soft x-ray fluorescence was recorded in the polarization plane of and normal to the incident photon beam using a high-resolution grazing-incidence grating spectrometer with a two-dimensional detector [4]. The bandpass of the exciting photon beam was set to ~0.3 eV, both for emission and absorption measurements, and the spectrometer resolution was ~0.5 eV.

## RESULTS AND DISCUSSION

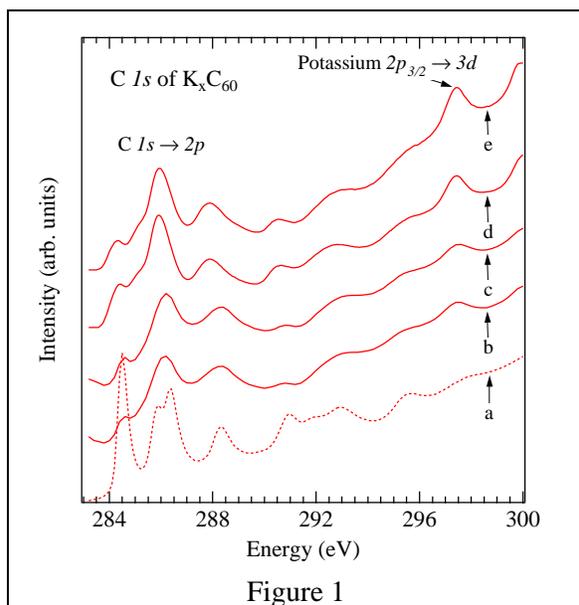


Figure 1

Figure 1 shows the soft x-ray absorption spectra for pure  $C_{60}$  and potassium doped  $C_{60}$  films obtained using total electron-yield detection. The lowest-energy peak in the  $C_{60}$  spectrum *a* corresponds to a transition from the  $C 1s$  to the LUMO. There are significant changes in the soft x-ray absorption spectrum upon deposition of potassium. The trend is in agreement with other XAS measurements, even though the saturation of K deposition was not reached in this case. The intensity contributed from the LUMO is reduced (see spectra *b*, *c*, *d* and *e* in figure 1) since the LUMO becomes occupied upon potassium doping, while the intensity of the  $K 2p \rightarrow 3d$  absorption (at about 297.4 eV) increases.

Figure 2 shows the  $C K$  emission of  $K_xC_{60}$  obtained at various excitation energies. The insert shows the x-ray absorption spectrum recorded for the same sample. In our previous investigations on pure  $C_{60}$  films, much larger shape variations were observed in  $C K$  emission of  $C_{60}$  with photon-excitation energy, and it was interpreted in terms of resonant inelastic x-ray scattering processes. Strong symmetry correlation including parity selection was verified. In contrast, here, the shape of the x-ray fluorescence spectra of  $K_xC_{60}$  film exhibits much less variations with excitation energy. This suggests that resonant inelastic x-ray scattering becomes less prominent due to the formation of metallic system upon potassium doping. Nevertheless, the survival of some shape variations in the photon-excited emission of  $K_xC_{60}$  suggests a certain degree of molecular character remaining.

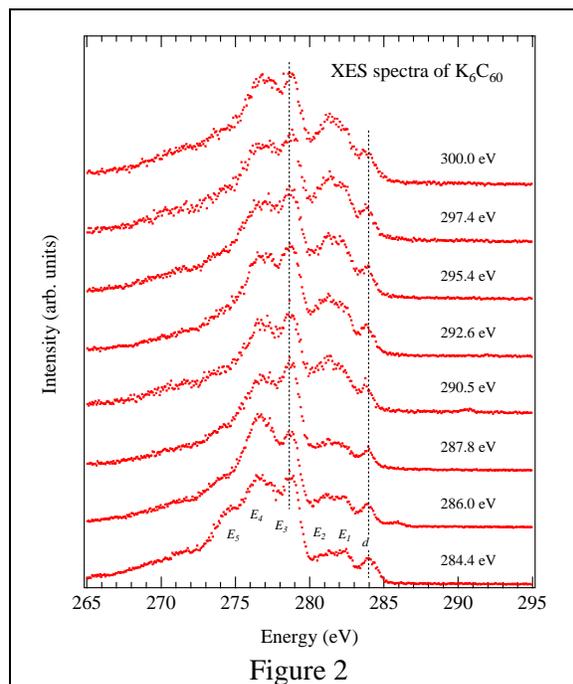


Figure 2

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This work was supported by the Swedish Natural Science Research Council (NFR), Department of Energy Materials Sciences Division Contract DE-AC03-76SF00098.

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